



Request date	:
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DIDEROT					
A REQUEST FOR SERVICE			Reference of the request::		
SCANNING ELECTRON MICROSCOPE (SEM) / LITHOGRAPHY Appareil: MEB- FEG Zeiss Supra 40					
Demandeur: NAME SURNAME Research team: If a student: Name of the person in charge :: - □ PHD □ M2 □ M1 E-mail: Telephone: office: □ ITODYS □ Collaboration : □ Extérieur (=hors ITODYS) :	<b>:</b> :	<u>If student requ</u>	est, validation of the supervisor:		
Sample information :	Type of samples :		□ conductor		
Number of samples :  Sample reference (numbering) :  Purpose of the observation:	☐ Thin film  ☐ Massive sample ☐ Pattern ☐ Powder (colloids) in Specify the type of sol		□ insulating □ carbon deposit □ platinum deposit dangerous□ Yes □ No		
Please indicate here in a few words the property or information that you are looking for by SEM analysis (size, shape, nanostructuring)					
Note: The sample must be dried (free of a excessive degassing in the analysis chamb		t for analysis, otherw	rise it will not be analyzed due to		
Desired time: Accep		Accepted deadline:	oted deadline:		
Observation results: Reseau 172-16.2.170 - Meb Public (Gam Derouich – Name of the person in charge)					
Form to be sent by email to:					

Jean-Christophe Lacroix: lacroix@univ-paris-diderot.fr (Scientific Manager)

Sarra Gam Derouich: sarra.derouich@univ-paris-diderot.fr (Engineer Head of MEB-lithography plateform)